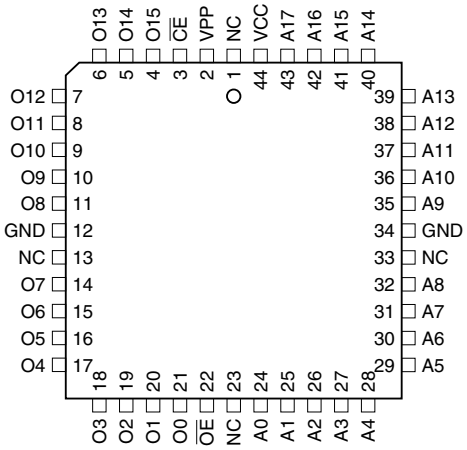
2. Pin configurations

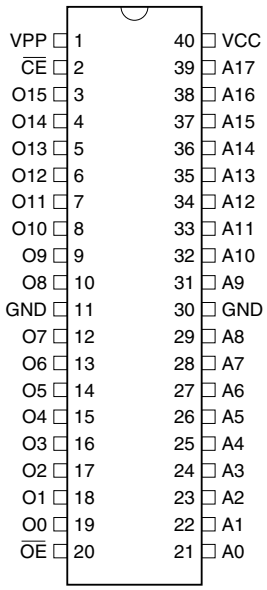
Pin name	Function
A0 - A17	Addresses
O0 - O15	Outputs
$\overline{CE}$	Chip enable
$\overline{OE}$	Output enable
NC	No connect

Note: Both GND pins must be connected

44-lead PLCC
Top view



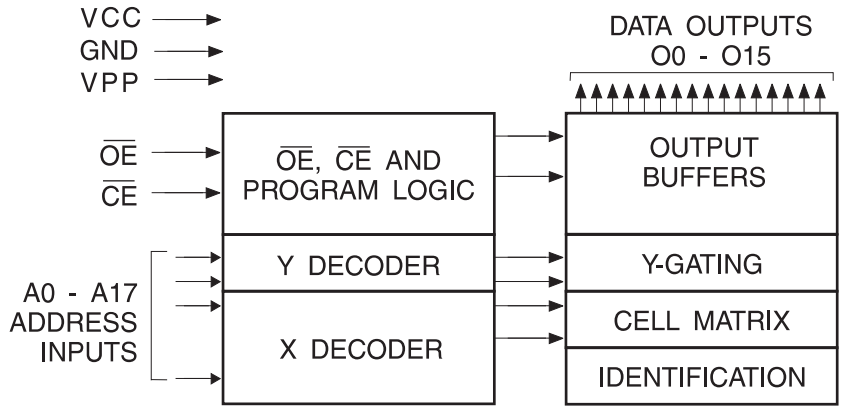
40-lead PDIP
Top view



3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device nonconformance. At a minimum, a 0.1µF, high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7µF bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

Figure 3-1. Block diagram



4. Absolute maximum ratings*

Temperature under bias	-55°C to +125°C
Storage temperature	-65°C to +150°C
Voltage on any pin with respect to ground	-2.0V to +7.0V(1)
Voltage on A9 with respect to ground	-2.0V to +14.0V(1)
V_{PP} supply voltage with respect to ground	-2.0V to +14.0V(1)

*NOTICE: Stresses beyond those listed under "Absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Maximum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is V_{CC} + 0.75V DC, which may overshoot to +7.0V for pulses of less than 20ns.

5. DC and AC characterisitcs

Table 5-1. Operating modes

Mode/Pin	$\overline{CE}$	$\overline{OE}$	Ai	V_{PP}	Outputs
Read	V_{IL}	V_{IL}	Ai	X(1)	D_{OUT}
Output disable	X	V_{IH}	X	X	High Z
Standby	V_{IH}	X	X	X(5)	High Z
Rapid program(2)	V_{IL}	V_{IH}	Ai	V_{PP}	D_{IN}
PGM verify	V_{IH}	V_{IL}	Ai	V_{PP}	D_{OUT}
PGM inhibit	V_{IH}	V_{IH}	X	V_{PP}	High Z
Product identification(4)	V_{IL}	V_{IL}	A9 = V_H(3) A0 = V_{IH} or V_{IL} A1 - A17 = V_{IL}	V_{CC}	Identification code

Notes:
1. X can be V_{IL} or V_{IH}.
2. Refer to the Programming characteristics.
3. V_H = 12.0 ± 0.5V.
4. Two identifier words may be selected. All Ai inputs are held low (V_{IL}), except A9, which is set to V_H, and A0, which is toggled low (V_{IL}) to select the manufacturer's identification word and high (V_{IH}) to select the device code word.
5. Standby V_{CC} current (I_{SB}) is specified with V_{PP} = V_{CC}. V_{CC} > V_{PP} will cause a slight increase in I_{SB}.

Table 5-2. DC and AC operating conditions for read operation

	Atmel AT27C4096	
	-55	-90
Industrial operating temperature (case)	-40°C - 85°C	-40°C - 85°C
V_{CC} power supply	5V ± 10%	5V ± 10%

Table 5-3. DC and operating characteristics for read operation

Symbol	Parameter	Condition	Min	Max	Units
I_{LI}	Input load current	V_{IN} = 0V to V_{CC}		± 1	µA
I_{LO}	Output leakage current	V_{OUT} = 0V to V_{CC}		± 5	µA
I_{PP1} (2)	V_{PP} (1) read/standby current	V_{PP} = V_{CC}		10	µA
I_{SB}	V_{CC} (1) standby current	I_{SB1} (CMOS) $\overline{CE}$ = V_{CC} ± 0.3V		100	µA
		I_{SB2} (TTL) $\overline{CE}$ = 2.0 to V_{CC} + 0.5V		1	mA
I_{CC}	V_{CC} active current	f = 5MHz, I_{OUT} = 0mA, $\overline{CE}$ = V_{IL}		40	mA
V_{IL}	Input low voltage		-0.6	0.8	V
V_{IH}	Input high voltage		2.0	V_{CC} + 0.5	V
V_{OL}	Output low voltage	I_{OL} = 2.1mA		0.4	V
V_{OH}	Output high voltage	I_{OH} = -400µA	2.4		V

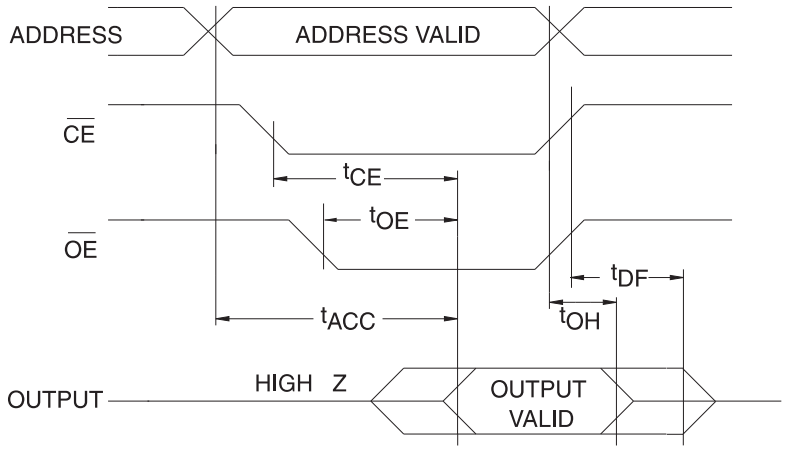
Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP}, and removed simultaneously with or after V_{PP}.
2. V_{PP} may be connected directly to V_{CC}, except during programming. The supply current would then be the sum of I_{CC} and I_{PP}.

Table 5-4. AC characteristics for read operation

			Atmel AT27C4096				
			-55		-90		
Symbol	Parameter	Condition	Min	Max	Min	Max	Units
t_{ACC} (1)	Address to output delay	$\overline{CE}$ = $\overline{OE}$ = V_{IL}		55		90	ns
t_{CE} (1)	$\overline{CE}$ to output delay	$\overline{OE}$ = V_{IL}		55		90	ns
t_{OE} (1)	$\overline{OE}$ to output delay	$\overline{CE}$ = V_{IL}		20		35	ns
t_{DF} (1)	$\overline{OE}$ or $\overline{CE}$ high to output float, whichever occurred first			20		20	ns
t_{OH} (1)	Output hold from address, $\overline{CE}$ or $\overline{OE}$, whichever occurred first		7		0		ns

Note: 1. See the AC waveforms for read operation diagram.

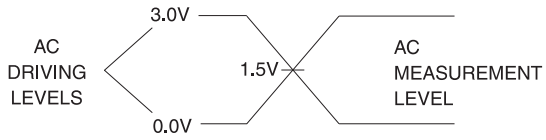
Figure 5-1. AC waveforms for read operation[1]



Notes:
1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.
2. $\overline{OE}$ may be delayed up to $t_{CE} - t_{OE}$ after the falling edge of $\overline{CE}$ without impact on t_{CE}.
3. $\overline{OE}$ may be delayed up to $t_{ACC} - t_{OE}$ after the address is valid without impact on t_{ACC}.
4. This parameter is only sampled, and is not 100% tested.
5. Output float is defined as the point when data is no longer driven.

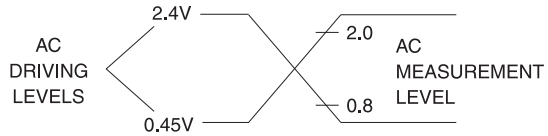
Figure 5-2. Input test waveforms and measurement levels

For -55 devices only:



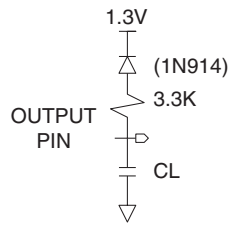
t_R, t_F < 5ns (10% to 90%)

For -90 devices:



t_R, t_F < 20ns (10% to 90%)

Figure 5-3. Output test load



Note: CL = 100pF including jig capacitance.

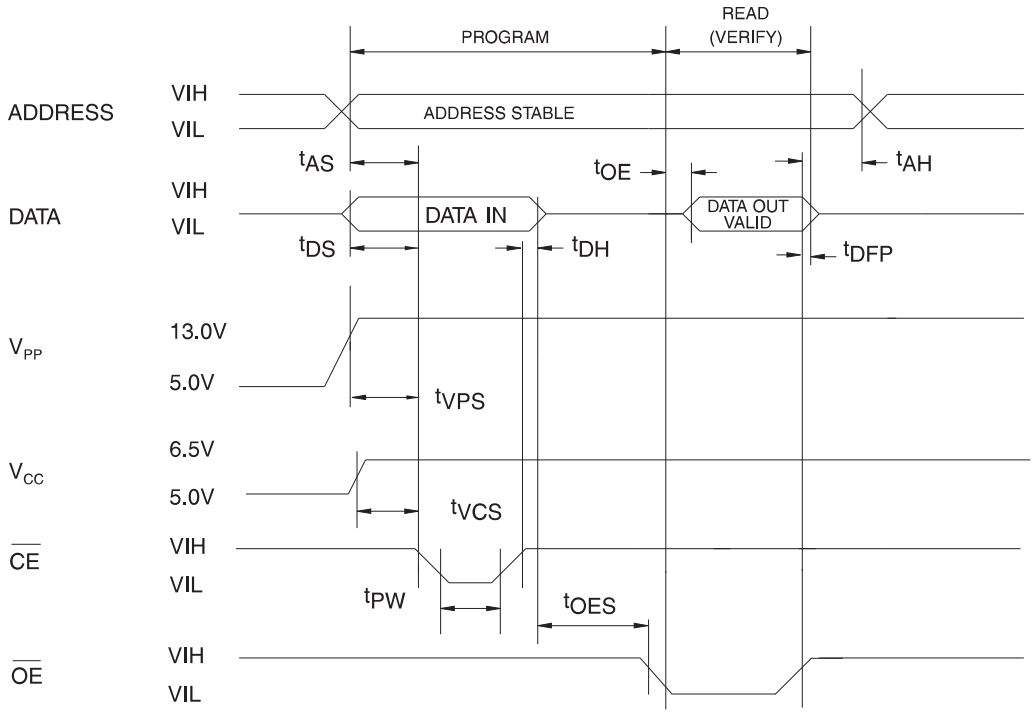
Table 5-5. Pin capacitance

f = 1MHz, T = 25°C[1]

Symbol	Typ	Max	Units	Conditions
C_{IN}	4	10	pF	V_{IN} = 0V
C_{OUT}	8	12	pF	V_{OUT} = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.

Figure 5-4. Programming waveforms[1]



Notes: 1. The input timing reference is 0.8V for V_{IL} and 2.0V for V_{IH}.

2. t_{OE} and t_{DFP} are characteristics of the device, but must be accommodated by the programmer.

3. When programming the Atmel AT27C4096, a 0.1µF capacitor is required across V_{PP} and ground to suppress spurious voltage transients.

Table 5-6. DC programming characteristics

T_A = 25 ± 5°C, V_{CC} = 6.5 ± 0.25V, V_{PP} = 13.0 ± 0.25V

Symbol	Parameter	Test conditions	Limits		Units
			Min	Max	
I_{LI}	Input load current	$V_{IN} = V_{IL}, V_{IH}$		±10	µA
V_{IL}	Input low level		-0.6	0.8	V
V_{IH}	Input high level		2.0	V_{CC} + 0.7	V
V_{OL}	Output low voltage	I_{OL} = 2.1mA		0.4	V
V_{OH}	Output high voltage	I_{OH} = -400µA	2.4		V
I_{CC2}	V_{CC} supply current (program and verify)			50	mA
I_{PP2}	V_{PP} supply current	$\overline{CE} = V_{IL}$		30	mA
V_{ID}	A9 product identification voltage		11.5	12.5	V

Table 5-7. AC programming characteristics

T_A = 25 ± 5°C, V_{CC} = 6.5 ± 0.25V, V_{PP} = 13.0 ± 0.25V

Symbol	Parameter	Test conditions[1]	Limits		Units
			Min	Max	
t_{AS}	Address setup time	Input rise and fall times : (10% to 90%) 20ns Input pulse levels 0.45V to 2.4V Input timing reference level: 0.8V to 2.0V Output timing reference level 0.8V to 2.0V	2		µs
t_{OES}	$\overline{OE}$ setup time		2		µs
t_{DS}	Data setup time		2		µs
t_{AH}	Address hold time		0		µs
t_{DH}	Data hold time		2		µs
t_{DFP}	$\overline{OE}$ high to output float delay[2]		0	130	ns
t_{VPS}	V_{PP} setup time		2		µs
t_{VCS}	V_{CC} setup time		2		µs
t_{PW}	$\overline{CE}$ program pulse width[3]		47.5	52.5	µs
t_{OE}	Data valid from $\overline{OE}$			150	ns
t_{PRT}	V_{PP} pulse rise time during programming		50		ns

Notes:
1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously with or after V_{PP}.
2. This parameter is only sampled, and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.
3. Program pulse width tolerance is 50µs ± 5%.

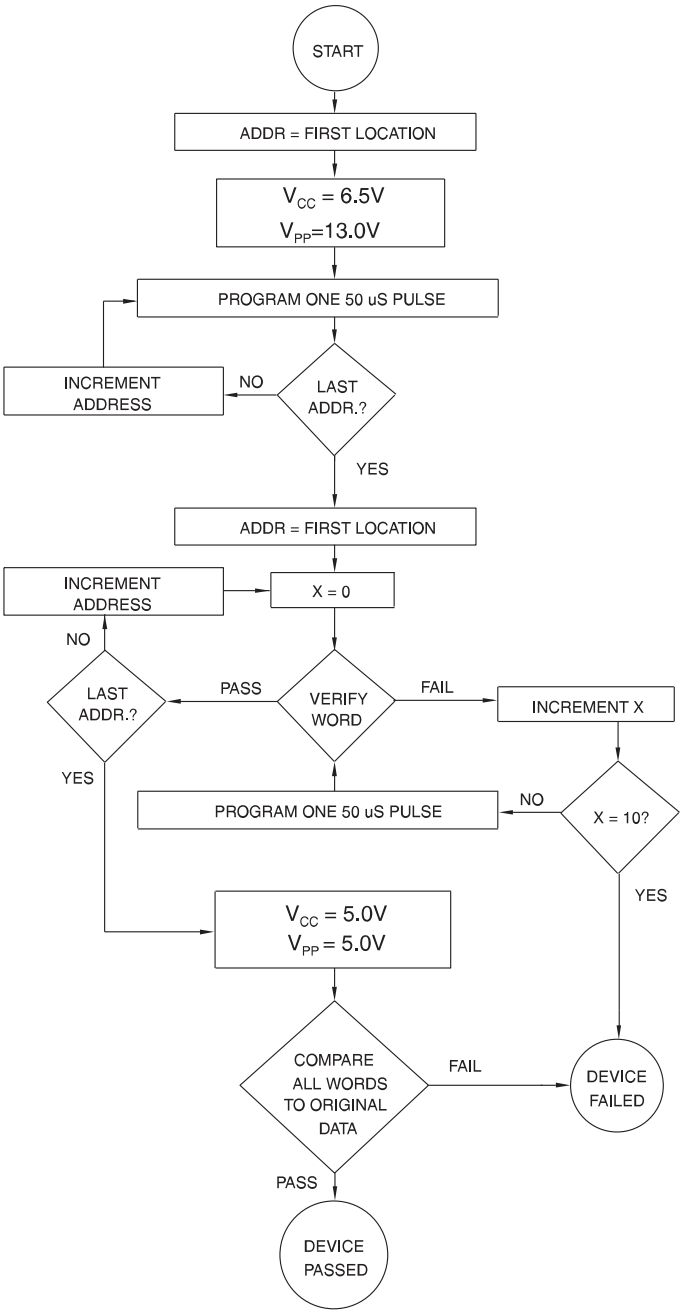
Table 5-8. The Atmel AT27C4096 intergrated product identification code

Codes	Pins										Hex data
	A0	O15-O8	O7	O6	O5	O4	O3	O2	O1	O0	
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device type	1	0	1	1	1	1	0	1	0	0	00F4

6. Rapid programming algorithm

A 50µs $\overline{CE}$ pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and V_{PP} is raised to 13.0V. Each address is first programmed with one 50µs $\overline{CE}$ pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 50µs pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked. V_{PP} is then lowered to 5.0V and V_{CC} to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.

Figure 6-1. Rapid programming algorithm



7. Ordering information

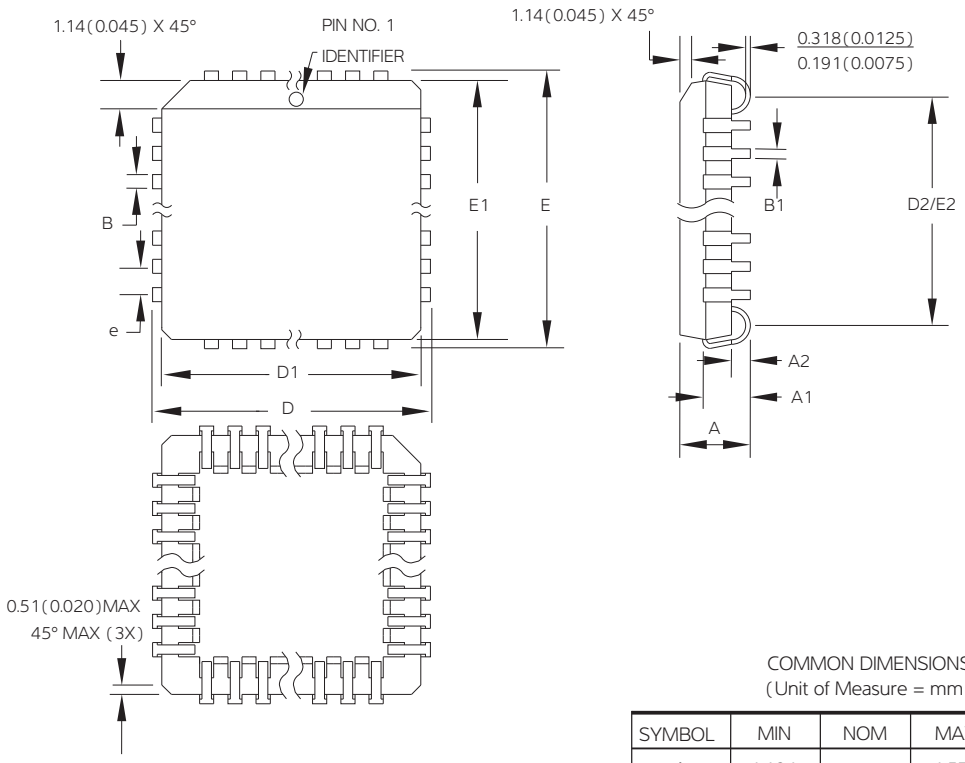
Green Package (Pb/halide-free)

t_{ACC} (ns)	I_{CC} (mA)		Atmel ordering code	Package	Lead finish	Operation range
	Active	Standby				
55	40	0.1	AT27C4096-55JU	44J	Matte tin	Industrial (-40°C to 85°C)
90	40	0.1	AT27C4096-90JU AT27C4096-90PU	44J 40P6	Matte tin	Industrial (-40°C to 85°C)

Package type	
44J	44-lead, plastic, J-leaded chip carrier (PLCC)
40P6	40-lead, 0.600" wide, plastic, dual inline package (PDIP)

8. Packaging information

44J – PLCC



COMMON DIMENSIONS
(Unit of Measure = mm)

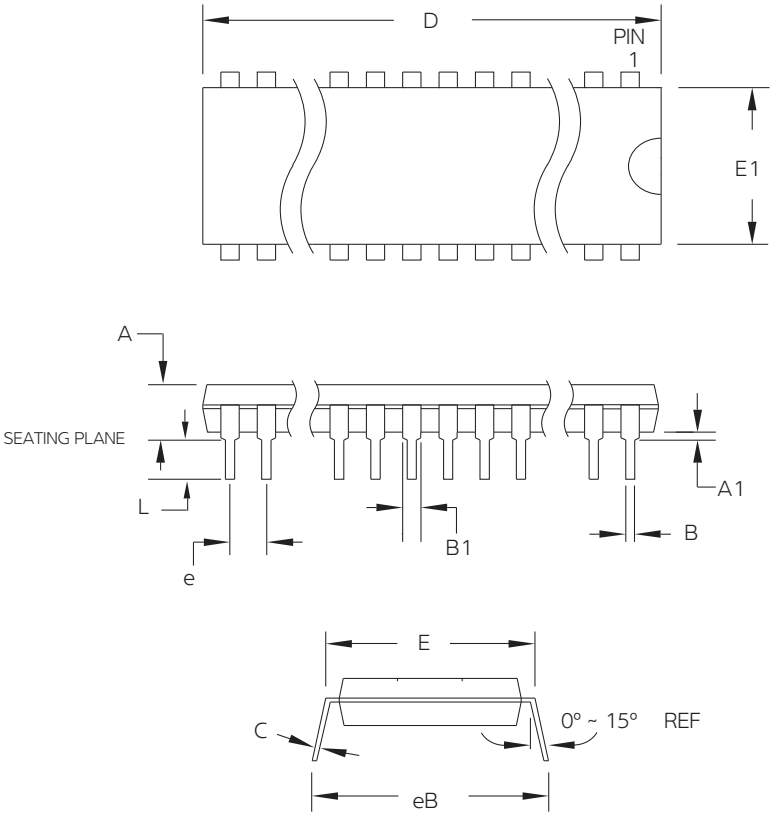
SYMBOL	MIN	NOM	MAX	NOTE
A	4.191	–	4.572	
A1	2.286	–	3.048	
A2	0.508	–	–	
D	17.399	–	17.653	
D1	16.510	–	16.662	Note 2
E	17.399	–	17.653	
E1	16.510	–	16.662	Note 2
D2/E2	14.986	–	16.002	
B	0.660	–	0.813	
B1	0.330	–	0.533	
e	1.270 TYP			

Notes:
1. This package conforms to JEDEC reference MS-018, variation AC
2. Dimensions D1 and E1 do not include mold protrusion. Allowable protrusion is .010"(0.254mm) per side. Dimension D1 and E1 include mold mismatch and are measured at the extreme material condition at the upper or lower parting line.
3. Lead coplanarity is 0.004" (0.102mm) maximum

10/04/01

	TITLE	DRAWING NO.	REV.
Package drawing contact: packagedrawings@atmel.com	44J, 44-lead, plastic J-leaded chip carrier (PLCC)	44J	B

40P6 – PDIP



COMMON DIMENSIONS
(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
A	–	–	4.826	
A1	0.381	–	–	
D	52.070	–	52.578	Note 2
E	15.240	–	15.875	
E1	13.462	–	13.970	Note 2
B	0.356	–	0.559	
B1	1.041	–	1.651	
L	3.048	–	3.556	
C	0.203	–	0.381	
eB	15.494	–	17.526	
e	2.540 TYP			

Notes:
1. This package conforms to JEDEC reference MS-011, variation AC
2. Dimensions D and E1 do not include mold flash or protrusion. mold flash or protrusion shall not exceed 0.25mm (0.010").

09/28/01

	TITLE	DRAWING NO.	REV.
Package drawing contact: packagedrawings@atmel.com	40P6, 40-lead (0.600"/15.24mm wide) Plastic dual inline package (PDIP)	40P6	B

9. Revision history

Doc. rev.	Date	Comments
0311J	04/2011	Remove VSOP package Add lead finish to ordering information
0311I	12/2007	

Atmel Corporation
2325 Orchard Parkway
San Jose, CA 95131
USA
Tel: (+1) (408) 441-0311
Fax: (+1) (408) 487-2600
www.atmel.com

Atmel Asia Limited
Unit 01-5 & 16, 19F
BEA Tower, Millennium City 5
418 Kwun Tong Road
Kwun Tong, Kowloon
HONG KONG
Tel: (+852) 2245-6100
Fax: (+852) 2722-1369

Atmel Munich GmbH
Business Campus
Parkring 4
D-85748 Garching b. Munich
GERMANY
Tel: (+49) 89-31970-0
Fax: (+49) 89-3194621

Atmel Japan
9F, Tonetsu Shinkawa Bldg.
1-24-8 Shinkawa
Chuo-ku, Tokyo 104-0033
JAPAN
Tel: (+81) (3) 3523-3551
Fax: (+81) (3) 3523-7581